

Reliability Analysis of a Diplexer with Improved Quality for the Prediction of Failure Probabilities

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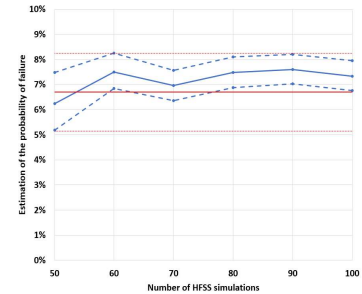
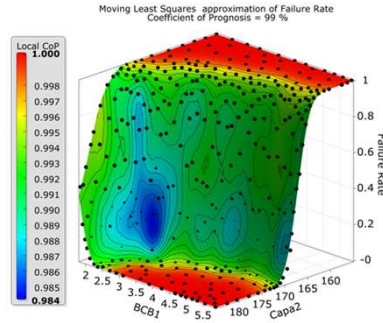
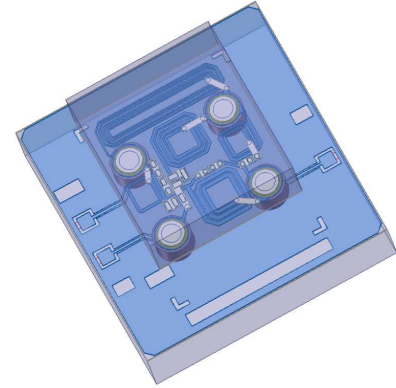


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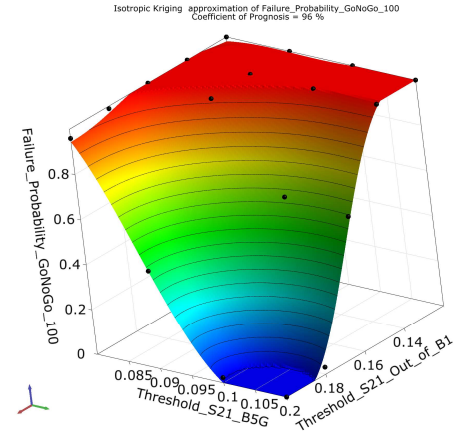
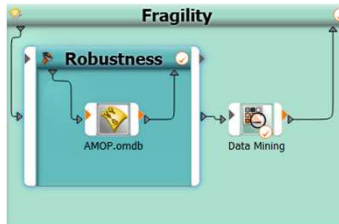
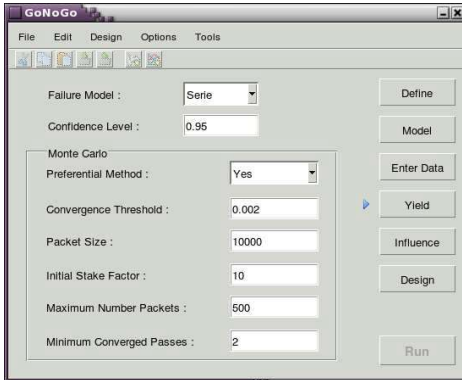
Agenda

- Reliability and Failure Probabilities: Motivation and Challenges
- The Diplexer Example
 - A Monte Carlo Reference Study
 - Robustness Evaluation using Latin Hypercube Sampling
 - Reliability Analysis with Fragility Surfaces
 - A Bayesian Model for Failure Risk Analysis
 - Application of the Bayesian Model to the Diplexer Case
 - A Sensitivity Analysis of Failure Probabilities
- Summary and Outlook



Reliability and Failure Probabilities

- Reliability is key for safety and for robust optimized products
- The key metric for reliability assessment is the probability of failure, which can be computed considering the variations, tolerances of the input parameters. Failure is usually defined by limits.
- Metamodels of failure probabilities require necessarily an estimation of the prediction quality
- These metamodels can be helpful in the whole product lifecycle from the early phase (layout / manufacturing) to product services (for example a product approaching failure limits during its lifetime)



The Diplexer Example

- A diplexer is a passive device sharing a single communication channel for two separate frequency bands, in our case 2G and 5G bands
- 12 output responses with defined limit values:
Failure is defined either when a loss exceeds a limit or when an attenuation is too weak
- From a previous sensitivity analysis, 4 geometric parameters can impact the product performances:
Capa2, **Meta2**, **BCB1**, **Meta1**

Table 2. Electrical characteristics and RF performance ($T_{amb} = 25\text{ }^{\circ}\text{C}$)

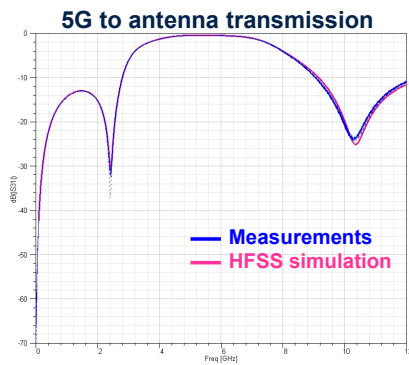
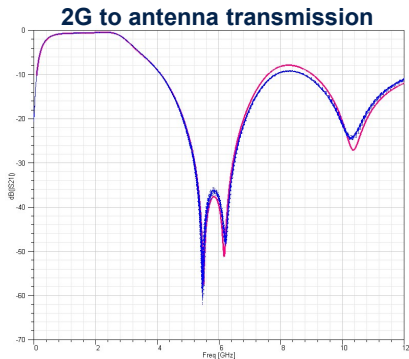
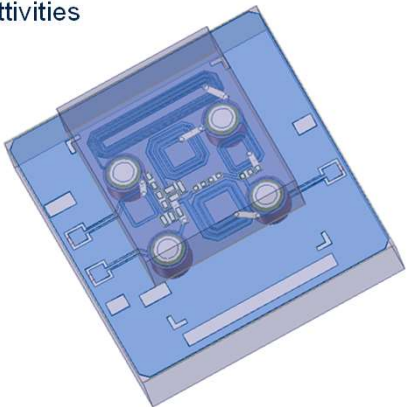
| Symbol | Parameter | Test condition | Value | | | Unit |
|--------------------------------|-------------------------------|--------------------|-------|------|--------|----------|
| | | | Min. | Typ. | Max. | |
| Pass band | | | | | | |
| f | 2 G band pass | | 2400 | | 2483.5 | MHz |
| | 5 G band pass | | 4900 | | 5850 | MHz |
| Z | Nominal impedance | | | 50 | | Ω |
| Return loss | | All ports | | | -17 | dB |
| S21 | 2 G to antenna insertion loss | 2400 to 2483.5 MHz | | 0.6 | 0.7 | dB |
| | 5 G to antenna insertion loss | 4900 to 5850 MHz | | 0.6 | 0.7 | dB |
| Attenuation | | | | | | |
| S21 | 2 G to antenna attenuation | 4900 to 5850 MHz | 20 | | | dB |
| S31 | 5 G to antenna attenuation | 2400 to 2483.5 MHz | 18 | | | dB |
| Out of band attenuation | | | | | | |
| S21 | 2 G to antenna attenuation | 5850 to 7000 MHz | 15 | | | dB |
| | | 7000 to 9500 MHz | 7 | | | |
| | | 9800 to 10500 MHz | 16 | | | |
| S31 | 5 G to antenna attenuation | 9800 to 11650 MHz | 11 | | | dB |

Technology cross section



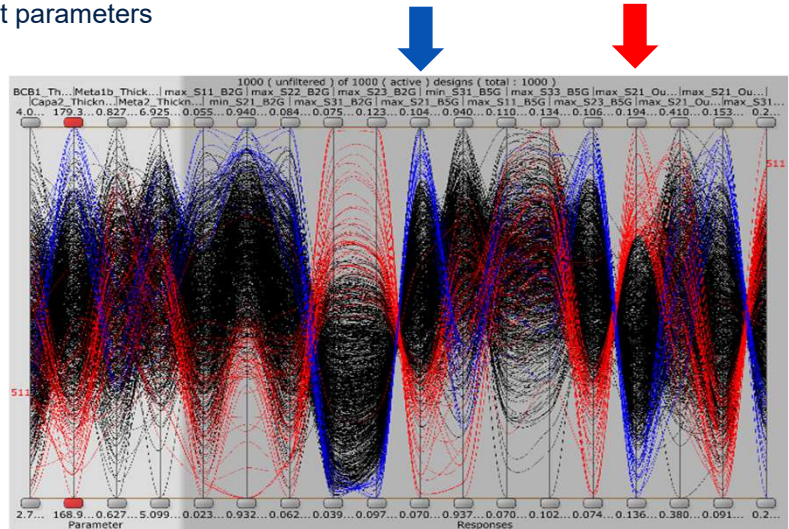
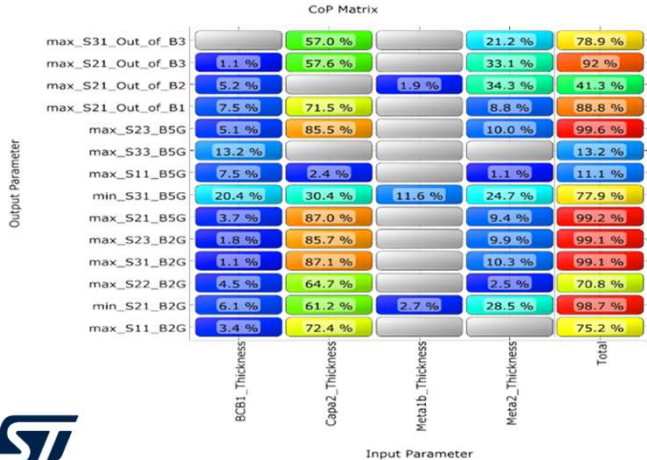
Numerical Model

- Electromagnetics physics \Rightarrow Ansys HFSS solver
- Parameterized geometric 3D model
 - Variables : thicknesses, conductivities, permittivities
 - **Enable parametric studies**
- Simulation results show excellent agreement with measurements
- Simulation statistics
 - Elapsed time \sim 5 hours (8 cores)
 - Memory \sim 25 Gb
- A brute-force Monte Carlo simulation is not effective



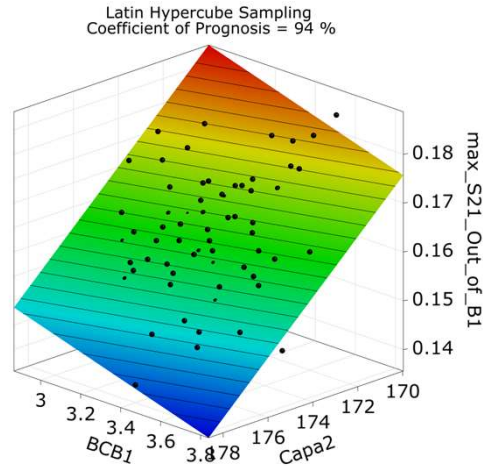
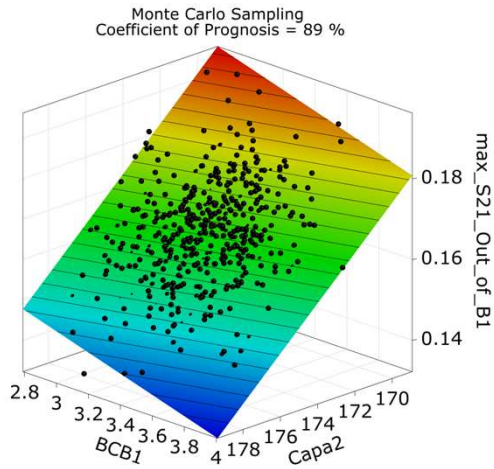
The Monte Carlo Reference Study

- 1000 simulations, 4 input parameters (geometric thicknesses BCB1, Capa2, Meta1b, Meta2)
- Gaussian distributions based on manufacturing tolerances
- Designs failed either for max_S21_B5G (blue lines in Parallel Coordinate Plots) or for max_S21_Out_of_B1 (red lines). Failure Rates 4.8% for max_S21_Out_of_B1 and 1.9% for max_S21_B5G; Total Failure Rate is 6.7%.
- High Coefficient of Prognosis (CoP) for these output parameters



Robustness Evaluation using Latin Hypercube Sampling

- 100 simulations using Latin Hypercube Design of Experiment instead of 1000 simulations
- Equivalent CoP, very similar MOPs
- Therefore, MOPs can be used for initial reliability analysis, verification can be done with the Latin hypercube sampling

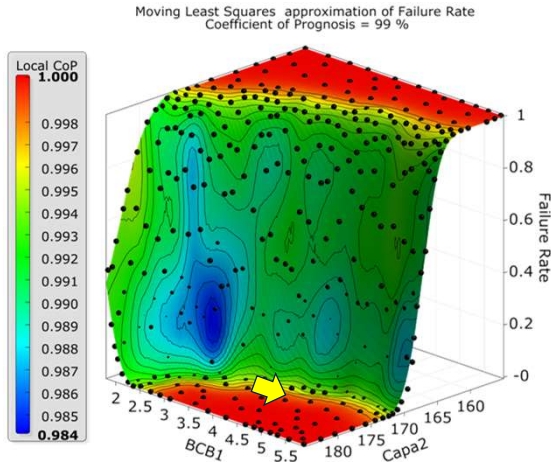


CoP Matrix

| | | | | |
|--------------------------------------|-----------------|-----------------|-----------------|--------|
| max_S21_Out_of_B1 Latin Hypercube | 9.4 % | 76.6 % | 7.5 % | 94.1 % |
| max_S21_Out_of_B1 Monte Carlo | 7.5 % | 71.5 % | 8.8 % | 88.8 % |
| max_S21_B5G Latin Hypercube | 3.7 % | 85.5 % | 9.3 % | 99 % |
| max_S21_B5G Monte Carlo | 3.7 % | 87.0 % | 9.4 % | 99.2 % |
| | BCB1_Thickness | Capa2_Thickness | Meta2_Thickness | Total |
| | Input Parameter | | | |

Reliability with Fragility Surfaces

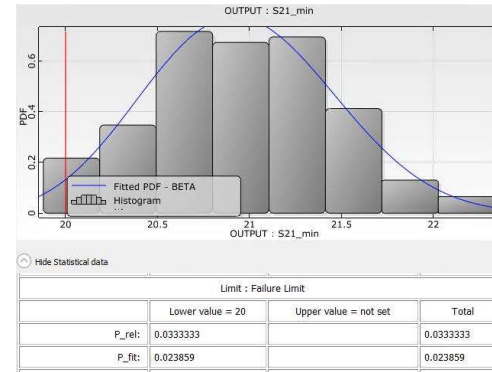
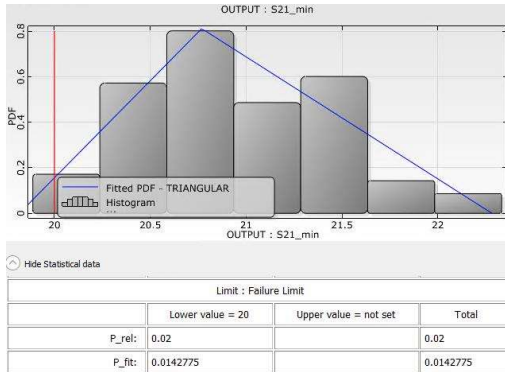
- High quality MOP is used for analysis of failure probabilities
- Fragility surfaces generated by varying the mean values of two important input parameters
- Increasing mean value BCB1 reduces the failure probability (indicated by yellow arrow on fragility surface)
- Verification with 5 mean value pairs and 100 simulation runs for each pair



| BCB1 | Capa2 | Failure rate (explicit simulations) | Failure rate (fragility surface) |
|------|--------|-------------------------------------|----------------------------------|
| 3.41 | 170.08 | 57 % | 62.5 % |
| 4.09 | 168.52 | 60 % | 58.8 % |
| 2.50 | 177.50 | 7 % | 12.5 % |
| 4.20 | 174.00 | 0 % | 0.3 % |
| 3.80 | 174.00 | 1 % | 1.7 % |

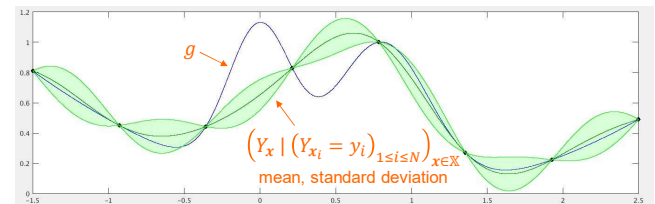
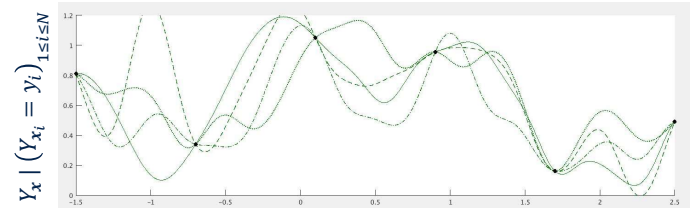
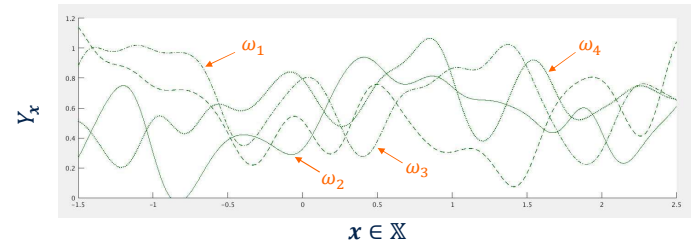
Influence of increasing BCB1 on other critical output parameter

- First step running 100 Ansys HFSS simulations lead to 2 failures for B5G
- Adding further 50 simulations (using Adaptive MOP technique) leads to 2 additional failures for B5G
- Total probability of failure using higher BCB1 mean value of $4.2 \mu\text{m}$ is about half of the initial failure rate !
- More simulations are necessary or other smart methods to reduce the number of necessary simulations and improve the prognosis quality



Bayesian interpolation

- A random field $(Y_x)_{x \in \mathbb{X}}$ is a random function defined over a factor space $\mathbb{X} \subseteq \mathbb{R}^d$, $d \in \mathbb{N}^*$
 \Rightarrow A realization of a random field is a function $Y(\omega)$, indexed by $\omega \in (\Omega, \mathbb{P})$ (sample space)
- The covariance of the random field fully defines the basis functions of the function space for the realizations and therefore their properties : regularity...
- The random field can be conditioned on $N \in \mathbb{N}^*$ observations $(Y_{x_i} = y_i)_{1 \leq i \leq N}$. It can be viewed as a learning process : realizations compatible with the observations are selected
- The conditioned random field can be used to interpolate an unknown function g defined over \mathbb{X}
 - g is supposed to be a realization of $(Y_x)_{x \in \mathbb{X}}$
 - Due to the finite information, several models are possible
 - The randomness can be interpreted as a modeling uncertainty



“Failure probability” random variable

- Factor space (\mathbb{X}, \mathbf{P}) , accident set $A = [T, +\infty[$, interpolation model $(Y_x)_{x \in \mathbb{X}}$ for an unknown function g

- Either p the failure probability, it can be written :

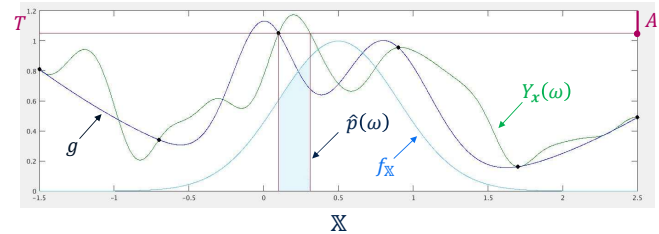
$$p = \int_{\mathbb{X}} \mathbb{I}_{g(x) \in A} d\mathbf{P}(x) = \int_{\mathbb{X}} \mathbb{I}_{g(x) \geq T} f_{\mathbb{X}}(x) dx$$

- The estimator \hat{p} is obtained substituting g with Y_x :

$$\hat{p}(\omega) = \int_{\mathbb{X}} \mathbb{I}_{Y_x(\omega) \in A} d\mathbf{P}(x)$$

- \hat{p} and the stochastic process $(Y_x)_{x \in \mathbb{X}}$ share the same randomness
 \Rightarrow The model uncertainty is propagated

- Adding data points reduces this uncertainty :



“Risk-of-failure probability” random variable

- To learn about the distribution of \hat{p} is difficult
 - The exact Bayesian inference of the posterior distribution of \hat{p} is intractable
 - Statistical inference from the analysis of realizations of \hat{p} is unreasonable in practice, as it requires to simulate trajectories of the random field
- The random variable \tilde{p} (risk-of-failure probability) is proposed as an alternative estimator

$$\tilde{p}(\alpha) = \int_{\mathbb{X}} \mathbb{I}_{\mathbb{P}(Y_x \in A) \geq \alpha} d\mathbf{P}(x)$$

- It is numerically efficient, as it only requires the knowledge of marginal distributions
- It stochastically dominates (in the convex order) the random variable $\hat{p} : \hat{p} \leq_{cx} \tilde{p}$

- They share the same mean value : $\mathbf{E}[\hat{p}] = \mathbf{E}[\tilde{p}]$
- Bounds on the quantiles of \hat{p} , more accurate than Markov bounds, can be derived from the quantile function $F_{\tilde{p}}^{-1}$ of \tilde{p} :
- From the inequalities above, one can easily derive credibility intervals for \hat{p}

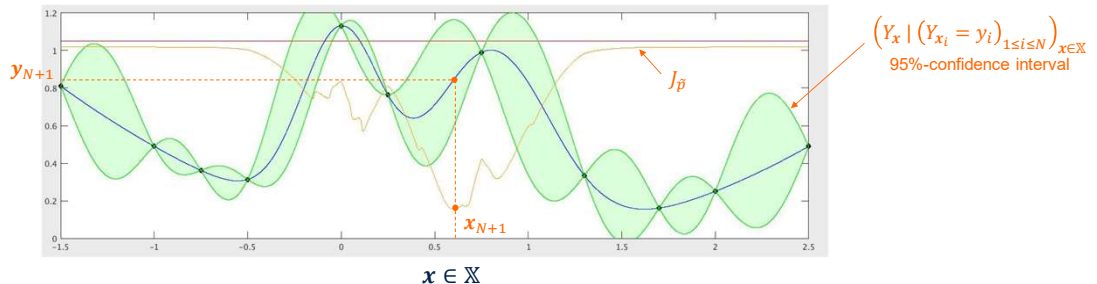
$$\frac{1}{\alpha} \int_0^{\alpha} F_{\tilde{p}}^{-1}(t) dt \leq F_{\tilde{p}}^{-1}(\alpha) \leq \frac{1}{1-\alpha} \int_{\alpha}^1 F_{\tilde{p}}^{-1}(t) dt$$

- The multi-response case ($K > 1$) can be easily managed using the Fréchet upper bound

$$\mathbb{P} \left(\bigcup_{k=1}^K Y_x^{(k)} \in A_k \right) \leq \sum_{k=1}^K \mathbb{P} \left(Y_x^{(k)} \in A_k \right)$$

Design of experiments

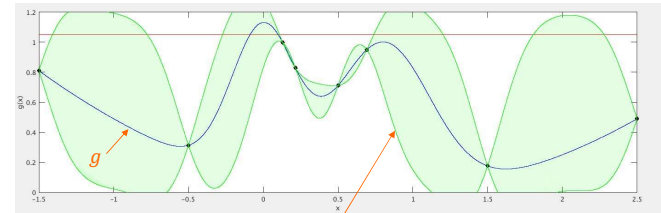
- In order to increase the model accuracy, new observations are required
- As each data point is computationally expensive to get, they should be carefully chosen to maximize the information obtained
- They are selected using a Stepwise Uncertainty Reduction (SUR) strategy
 - Intended to reduce the uncertainty on the estimation of \hat{p}
 - The design of experiment, of size N , is enriched sequentially
 - A cost function $J_{\hat{p}}$, based on $\text{var}[\hat{p}]$, is minimized to identify the optimal candidate (x_{N+1}, y_{N+1})
 - Global optimization is performed using a genetic algorithm



Gradient-enhanced Bayesian interpolation

- HFSS solver is based on the transfinite element method
 - The gradient of the S-parameters is a by-product of the simulation
 - It is not a finite-difference approximation (that would be computationally expensive to get for a high-dimensional factor space \mathbb{X})
- A random field can also be conditioned on the gradients obtained at the observation points $(\vec{\nabla}Y_{x_i} = \gamma_i)_{1 \leq i \leq N}$
- This additional information is a manna !
 - It increases the quality of the predictions
 - The selection process is more stringent
 ⇒ The predictive uncertainty is significantly reduced

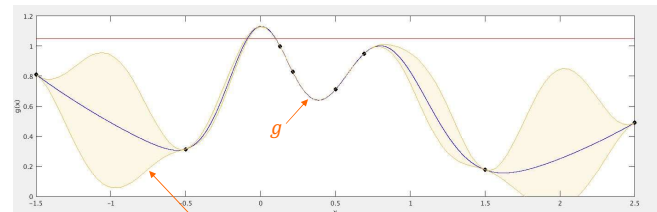
Without derivatives



$$(Y_x | (Y_{x_i} = y_i)_{1 \leq i \leq N})_{x \in \mathbb{X}}$$

95%-confidence interval

With derivatives



$$(Y_x | (Y_{x_i} = y_i \cap \vec{\nabla}Y_{x_i} = \gamma_i)_{1 \leq i \leq N})_{x \in \mathbb{X}}$$

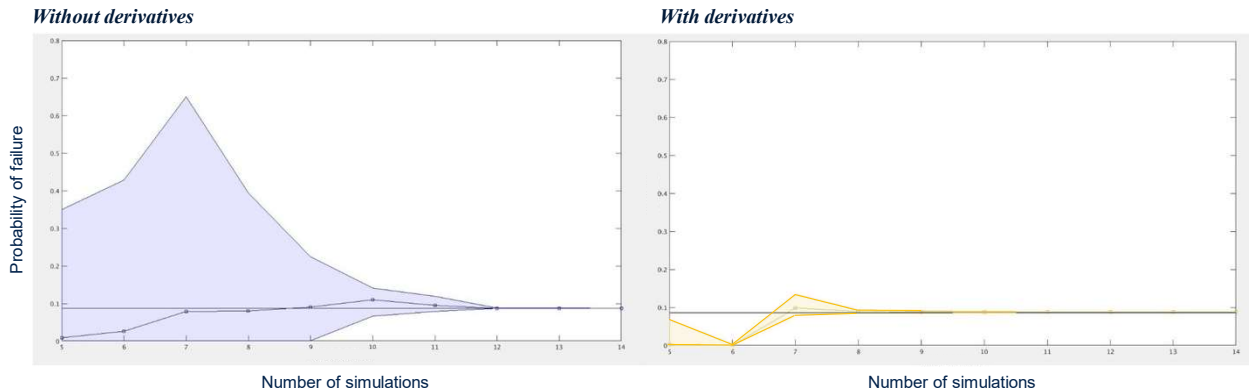
95%-confidence interval

Toy model

- We consider the following illustrative example :

$$g : \begin{cases} \mathbb{R} \rightarrow \mathbb{R} \\ x \mapsto (0.4x - 0.3)^2 + e^{-11x^2} + e^{-5(x-0.8)^2} \end{cases} \quad T = 1.05 \quad f_{\mathbb{X}} = \mathcal{N}(0.5, 0.4^2)$$

- A sequential design of experiments is built using the SUR strategy
- Convergence of the results are compared, without and with derivatives
⇒ The derivative information significantly improves the predictions

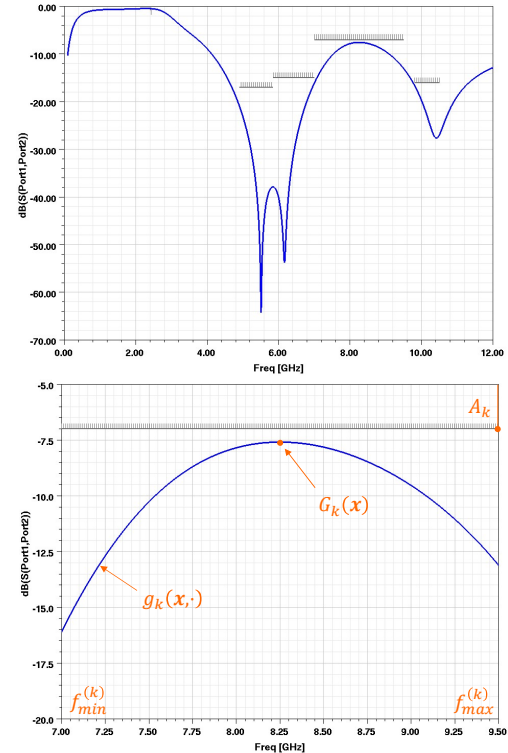


Extremal responses

- The product datasheet bears upon the modules $|S_{ij}|$ of the S-parameters S_{ij} over specific frequency ranges $\mathcal{F}_k = [f_{min}^{(k)}, f_{max}^{(k)}]$, $1 \leq k \leq K$
- We consider the restrictions of $|S_{ij}|$ to $\mathcal{F}_k : (x, f) \mapsto g_k(x, f) = |S_{ij}|_{\mathcal{F}_k}(x, f)$
- It can be assigned to each function g_k an accident set A_k : specification k is not met when $g_k \in A_k$
- In case the accident set A_k is connected, it is possible simplify the problem excluding the frequency parameter from the analysis, by introducing extremal responses

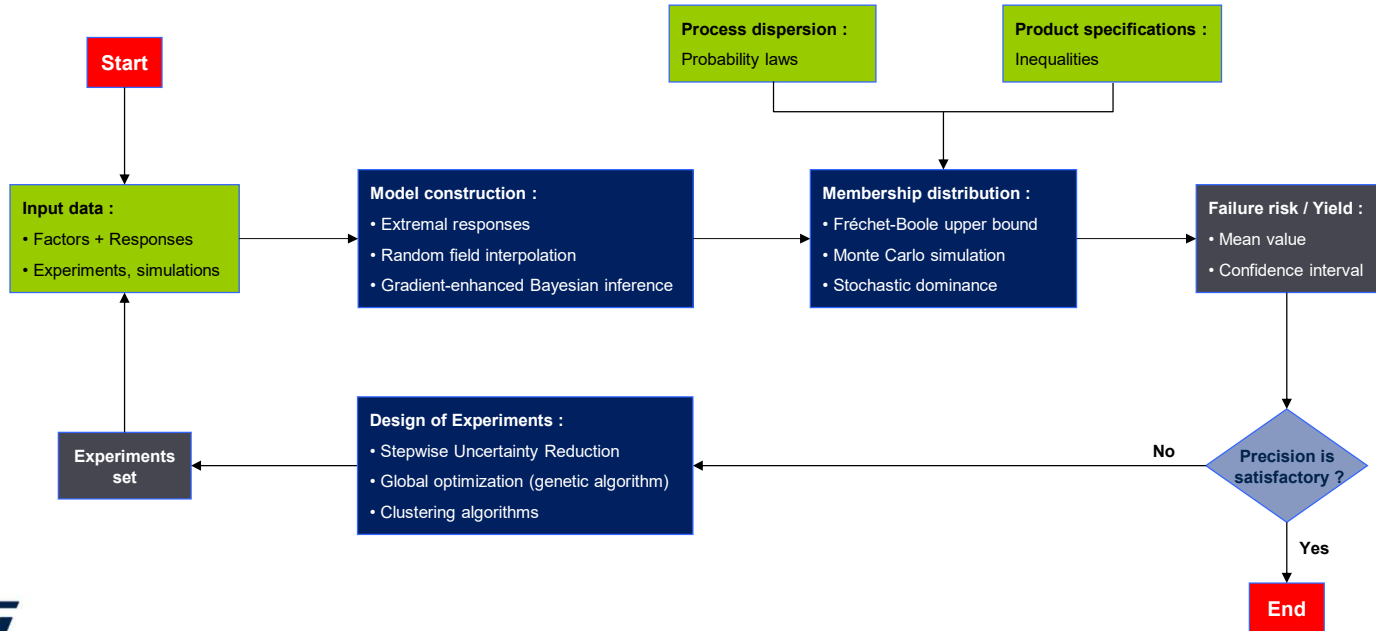
$$G_k = \max_{f \in \mathcal{F}_k} [g_k(\cdot, f)]$$

- **We have established the following result :**
 - G_k is differentiable almost everywhere on \mathbb{X}
 \Rightarrow It can be reasonably represented with a differentiable random field
 - An explicit expression for the gradient $\vec{\nabla} G_k$ has been derived



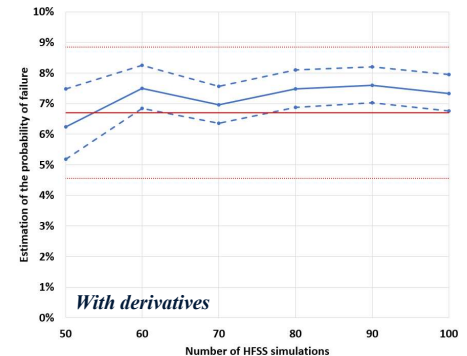
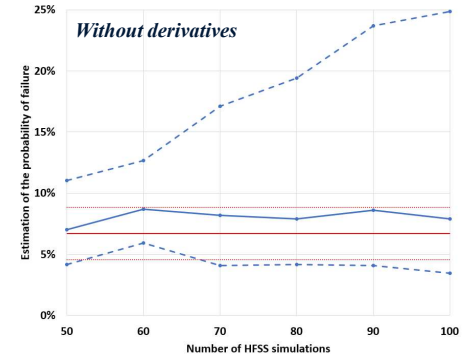
Failure risk analysis

- Modeling flow for the GoNoGo application



Application to the duplexer case

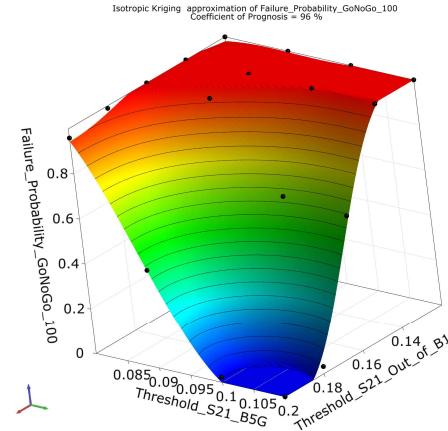
- A Brute-Force Monte-Carlo simulation is performed as a reference :
 - 1000 samples
 - Duration ~ 1 month
 - Failure Probability estimation :
 $E[\hat{p}_{MC}] = 6.7\%$, $\hat{p}_{MC} \in [4.15\%, 8.25\%]$ (95% confidence interval)
- Uncertainty propagation is crucial to assess the model quality for the quantity of interest
- Using the gradient information drastically improve the prediction capabilities of the model :
 - 100 samples
 - Failure Probability estimation :
 $E[\hat{p}] = 7.33\%$, $\hat{p} \in [6.77\%, 7.95\%]$ (95% confidence interval)
- The number of simulations required to (significantly) outperform the Monte-Carlo confidence interval is (at least) an order of magnitude lower



Threshold dependence of the failure probability

Table 2. Electrical characteristics and RF performance ($T_{amb} = 25\text{ }^{\circ}\text{C}$)

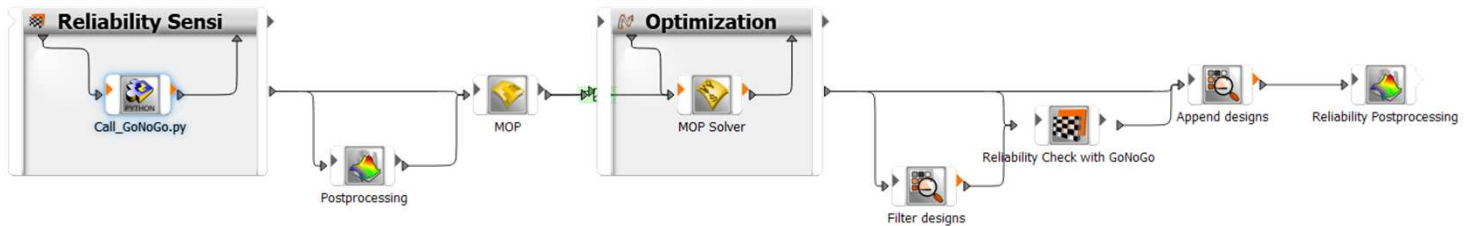
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- The datasheet can be optimized, with a yield constraint, by testing different threshold values
- This leads to different failure probabilities for the same input parameter distributions
- Using the precise failure probabilities calculated with GoNoGo and coupling to optiSLang makes this type of study simple

Summary and outlook

- Reliability analysis including the prediction of failure probabilities is nowadays feasible:
 - Methods and algorithms to reduce the number of necessary simulations are key
 - The MOP can be used to build fragility surfaces to understand the transition region in parameter space
 - Verification, especially in the transition region from failure to non failure, is important
 - Ansys HFSS derivatives, using a rigorous Bayesian inference framework, can be used for an improved quality for the prediction of failure probabilities
 - Coupling GoNoGo with optiSLang enables to study for example the impact of the threshold value
- These methods can be very helpful for the reduction of the production yield losses and for the adaptation to specific requirements
- For many parameters, an automation process like outlined below will be helpful



Outline for a future approach of the optimization for the production yield

Thank you very much for your attention!